

TOSHIBA Transistor Silicon NPN Epitaxial Type

# 2SC5906

High-Speed Switching Applications  
 DC-DC Converter Applications  
 Strobe Applications

- High DC current gain:  $h_{FE} = 200$  to  $500$  ( $I_C = 0.5$  A)
- Low collector-emitter saturation voltage:  $V_{CE(sat)} = 0.2$  V (max)
- High-speed switching:  $t_f = 25$  ns (typ.)

### Absolute Maximum Ratings (Ta = 25°C)

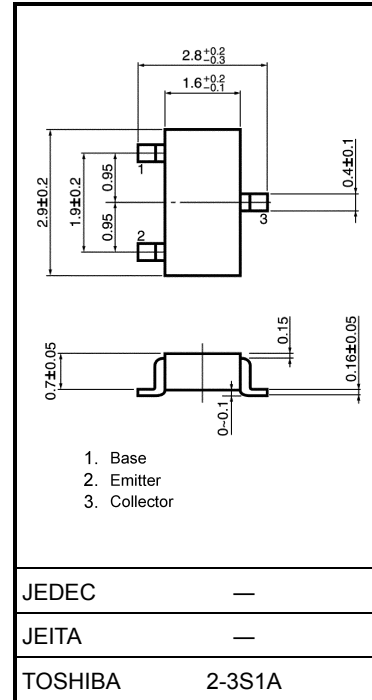
Characteristics		Symbol	Rating	Unit
Collector-base voltage		$V_{CBO}$	50	V
Collector-emitter voltage		$V_{CEX}$	50	V
Collector-emitter voltage		$V_{CEO}$	30	V
Emitter-base voltage		$V_{EBO}$	7	V
Collector current	DC	$I_C$	4	A
	Pulse	$I_{CP}$	7	
Base current		$I_B$	0.4	A
Collector power dissipation	DC	$P_C$ (Note 1)	0.8	W
	$t = 10$ s		1.25	
Junction temperature		$T_j$	150	°C
Storage temperature range		$T_{stg}$	-55 to 150	°C

Note 1: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm<sup>2</sup>)

Note 2: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

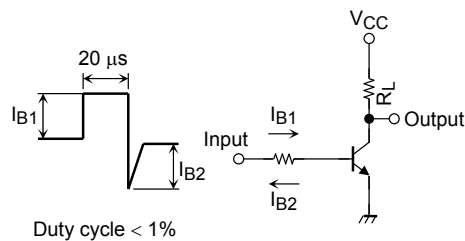
Unit: mm



Weight: 0.01 g (typ.)

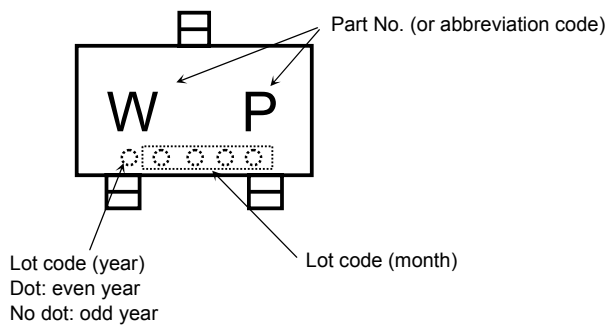
## Electrical Characteristics (Ta = 25°C)

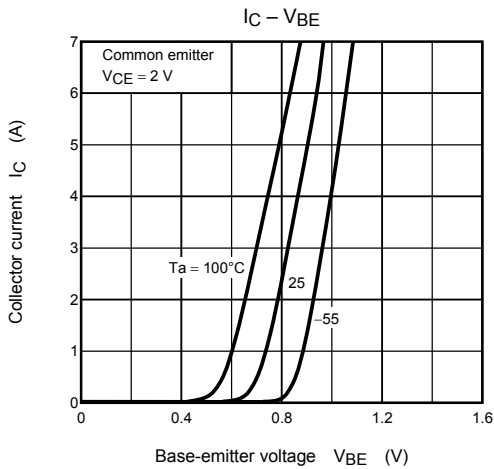
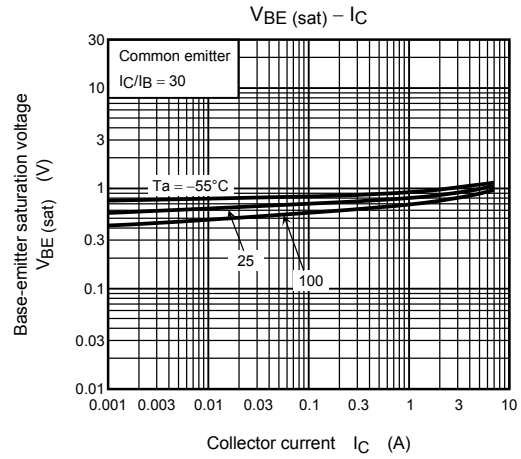
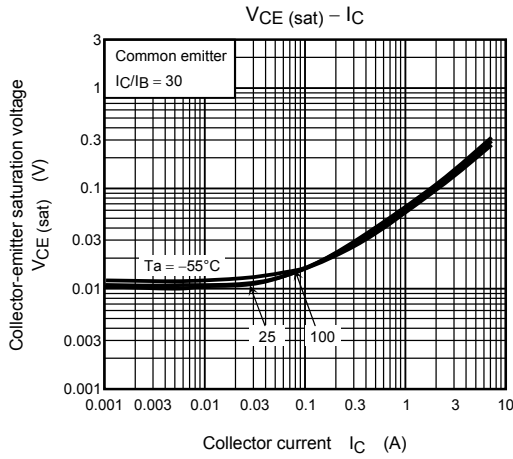
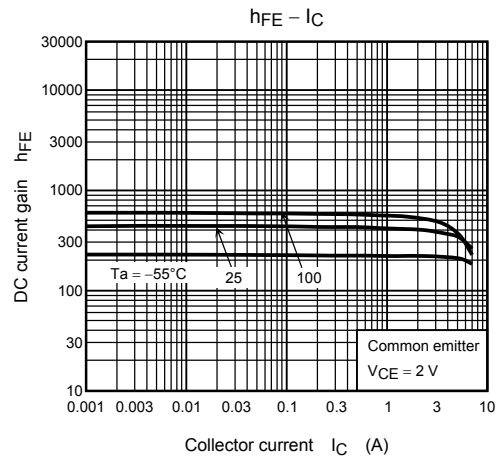
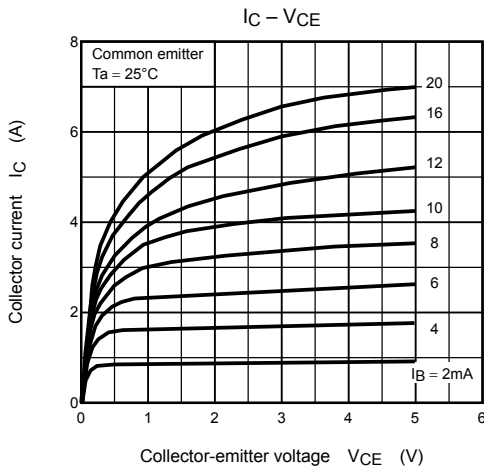
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current	$I_{CBO}$	$V_{CB} = 50 \text{ V}, I_E = 0$	—	—	0.1	$\mu\text{A}$
Emitter cut-off current	$I_{EBO}$	$V_{EB} = 7 \text{ V}, I_C = 0$	—	—	0.1	$\mu\text{A}$
Collector-emitter breakdown voltage	$V_{(BR)CEO}$	$I_C = 10 \text{ mA}, I_B = 0$	30	—	—	V
DC current gain	$h_{FE} (1)$	$V_{CE} = 2 \text{ V}, I_C = 0.5 \text{ A}$	200	—	500	
	$h_{FE} (2)$	$V_{CE} = 2 \text{ V}, I_C = 1.6 \text{ A}$	120	—	—	
Collector-emitter saturation voltage	$V_{CE(sat)}$	$I_C = 1.6 \text{ A}, I_B = 53 \text{ mA}$	—	—	0.20	V
Base-emitter saturation voltage	$V_{BE(sat)}$	$I_C = 1.6 \text{ A}, I_B = 53 \text{ mA}$	—	—	1.10	V
Collector output capacitance	$C_{ob}$	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$	—	35	—	pF
Switching time	Rise time	$t_r$	—	55	—	ns
	Storage time	$t_{stg}$	—	310	—	
	Fall time	$t_f$	—	25	—	

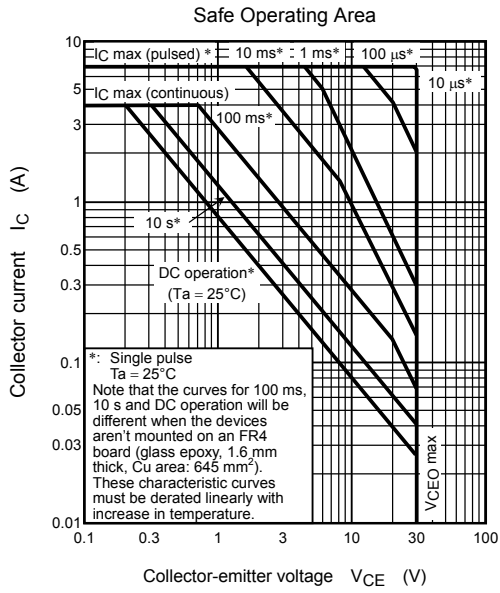
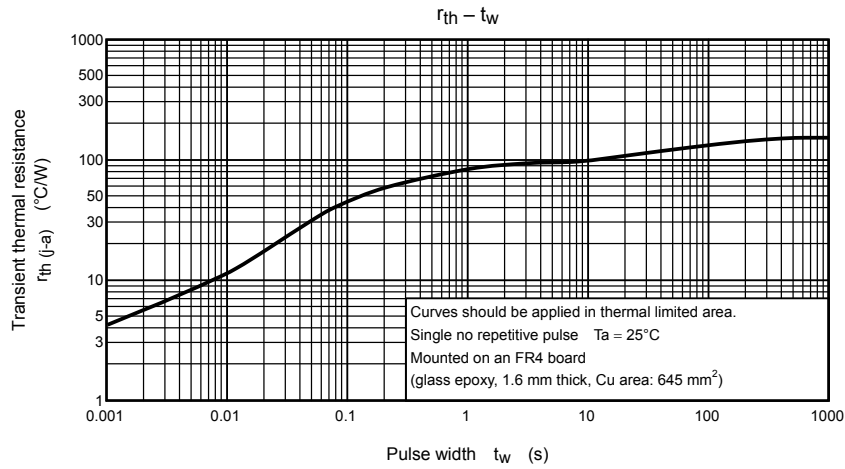


**Figure 1 Switching Time Test Circuit & Timing Chart**

## Marking







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